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Electrodeposition of Nb₃Sn thin films

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Electrodeposition of Nb_3Sn thin films

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Summer School Project

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Aim of the project



<https://news.fnal.gov/wp-content/uploads/2019/07/srf-acceleration-cavity-05-0438-10D.hr.jpg> 8/16/2019

Electrodeposition from aqueous electrolytes

STEP 1:
Electrodeposition

- GOAL:**
Deposition on Nb substrate
of 3 precursor layers:
- Cu seed layer
 - Sn layer
 - Cu barrier layer

STEP 2:
Baking in inert atmosphere

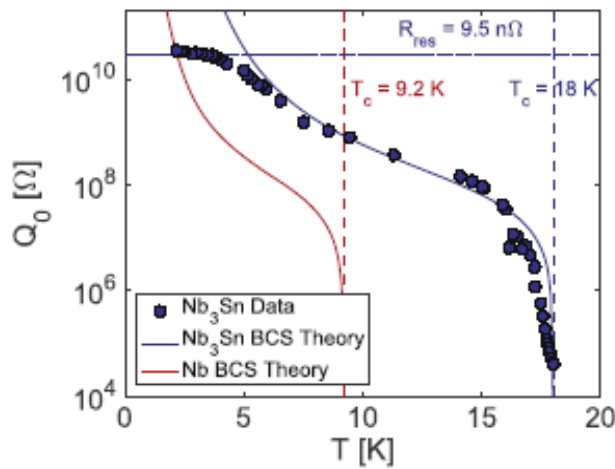
GOAL:
Formation of the
superconductive phase
 Nb_3Sn during the thermal
treatment

Nb SRF cavities are reaching their performance limit



Nb_3Sn is the best candidate to
replace Nb as superconducting
material for SRF cavities

- Nb_3Sn :
- $B_{C20} = 30 \text{ T}$
 - $T_c = 18 \text{ K}$



How to deposit Nb_3Sn ?

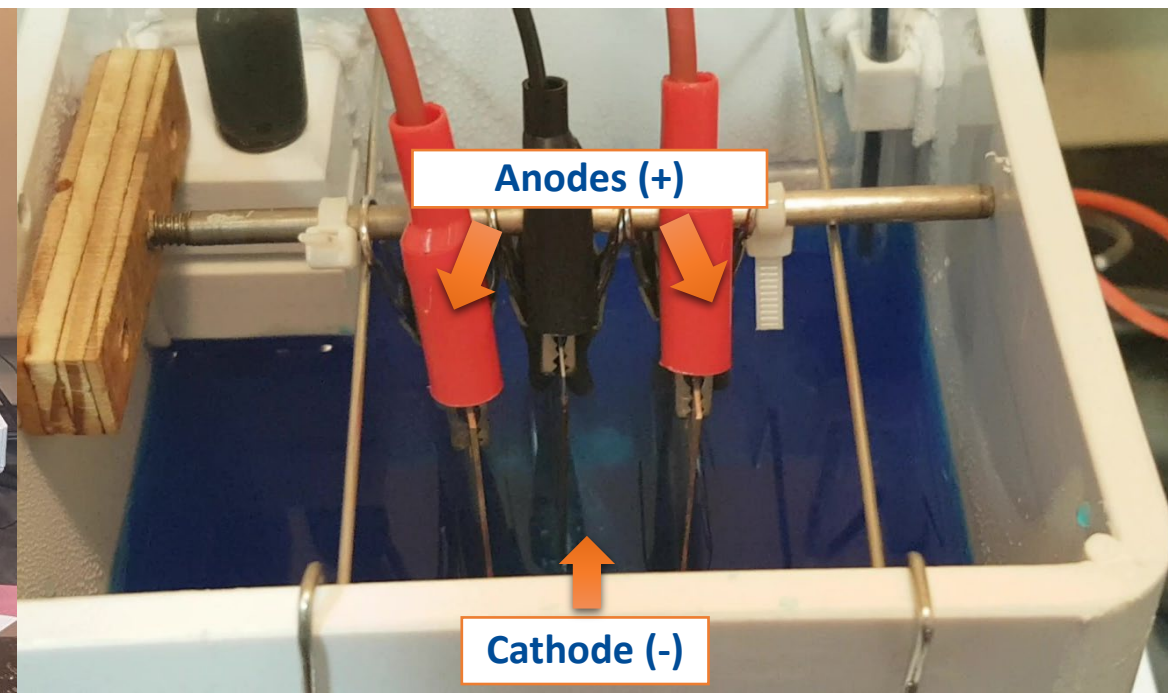
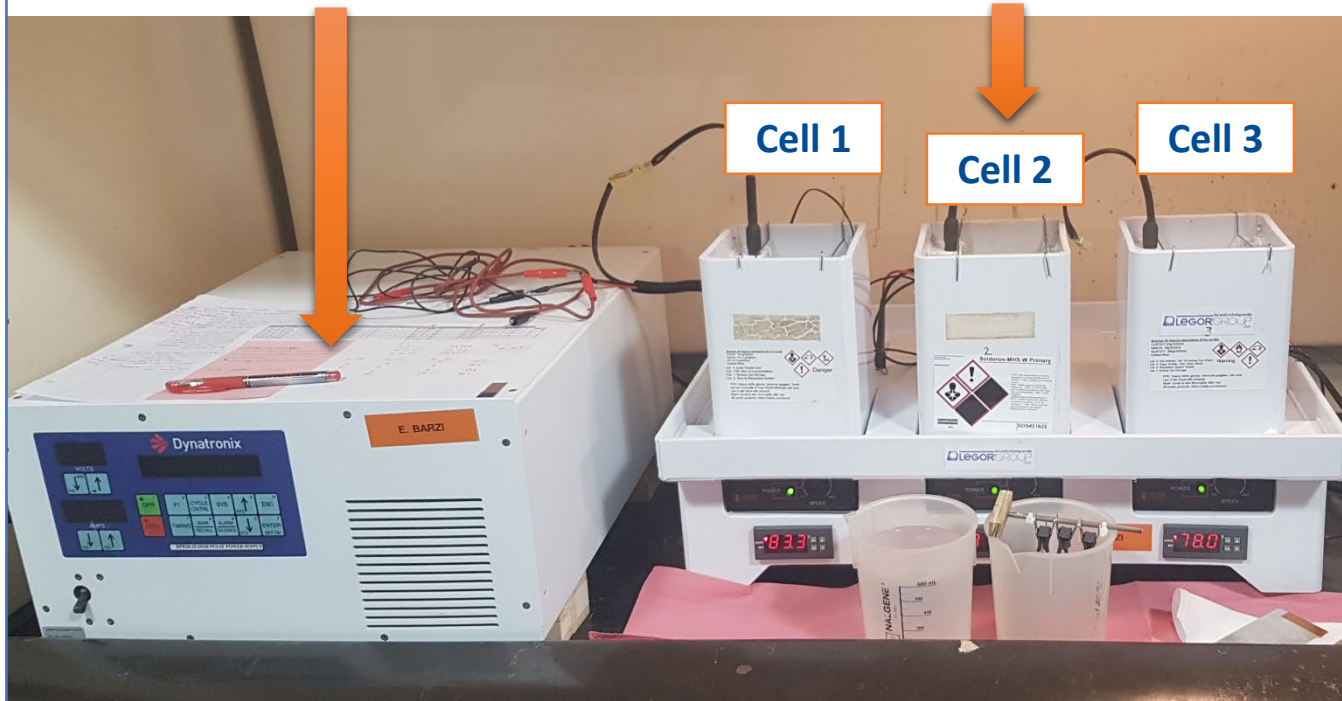


Experimental Setup: Electrochemical Cell

Power Supply

Electrochemical Cells

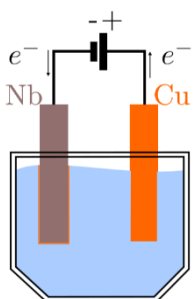
3 Electrodes Geometry



STEP 1

Deposition of Cu seed layer

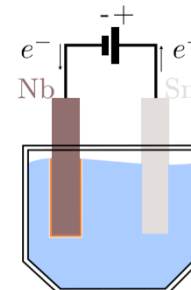
- HCl: 67.8ml
- H₂SO₄: 217.4ml
- CuSO₄: 120g
- H₂O: up to 2L



STEP 2

Deposition of Sn layer

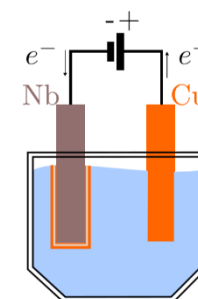
- Solderon Acid HC: 430ml
- Solderon Tin HS-300: 333ml
- Solderon MHS-W: 200ml
- H₂O: up to 2L



STEP 3

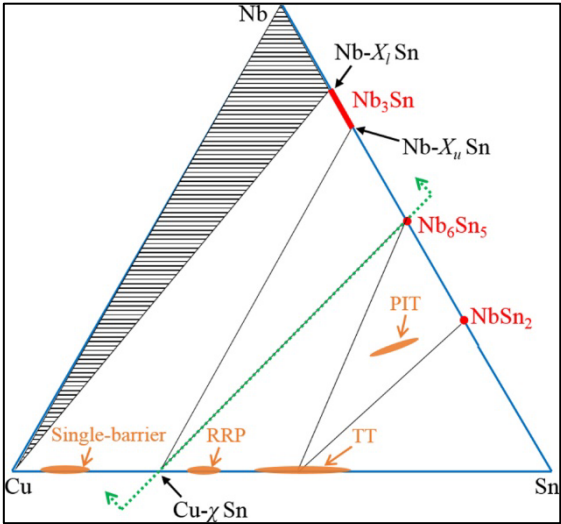
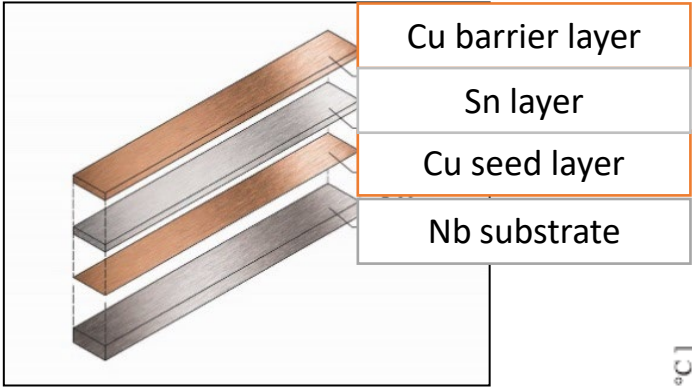
Deposition of Cu barrier layer

- Cu₂P₂O₇: 52g
- NaNO₃: 10g
- Na₄P₂O₇: 360g
- H₂O: up to 2L

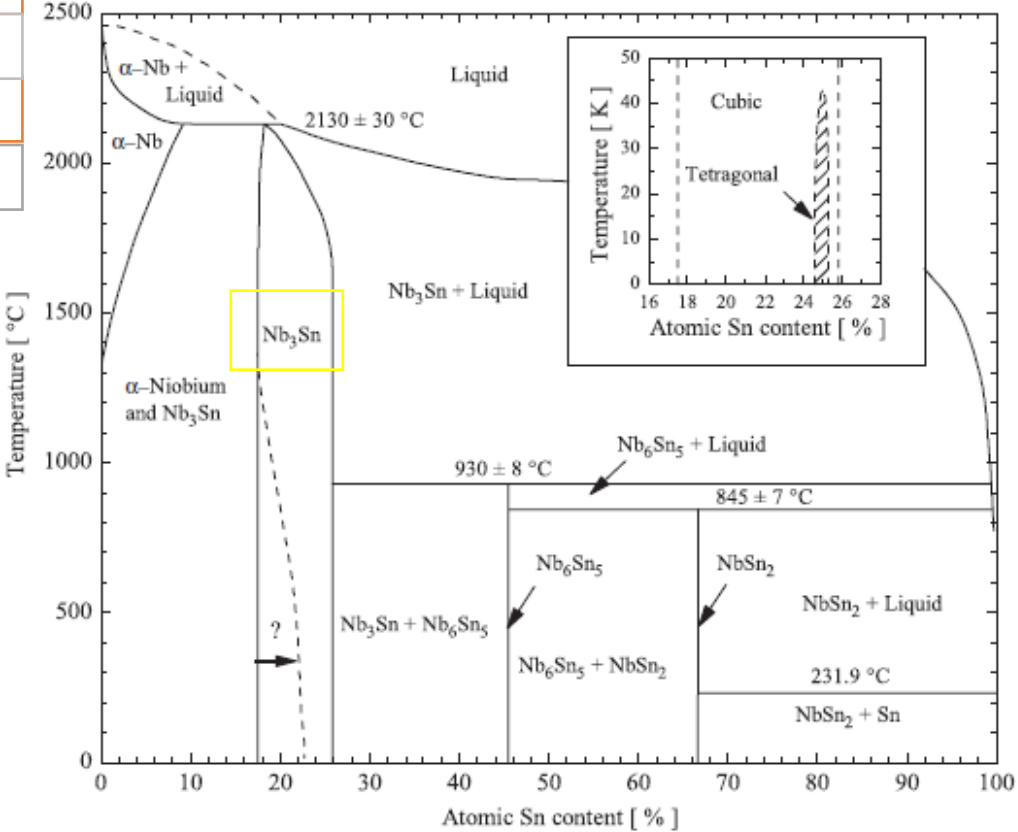


Experimental Setup: Baking

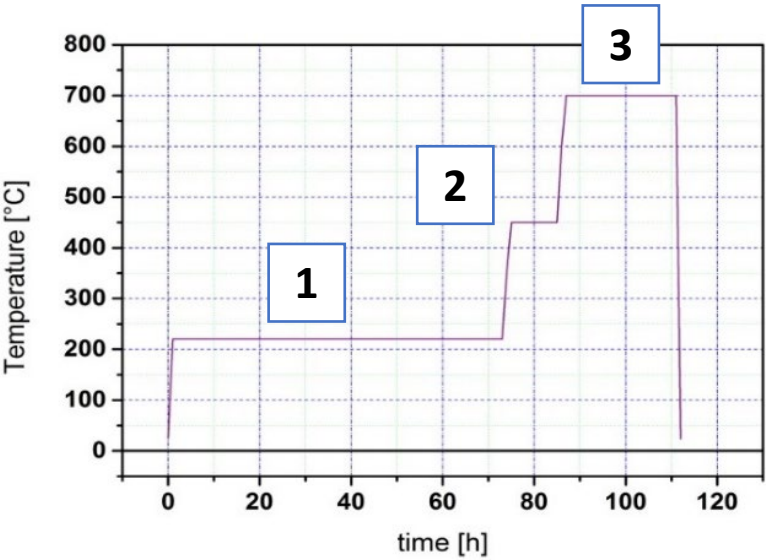
Final Structure



Nb-Sn Phase Diagram



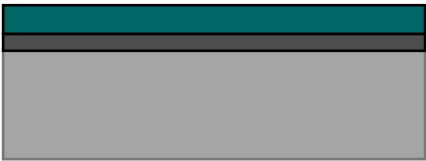
Thermal Treatment



1] Relaxation of internal stresses

2] Melting of Sn layer and interdiffusion Cu-Nb

3] Formation of Nb_3Sn phase



Bronze

Nb_3Sn and Nb/Sn phases

Nb substrate

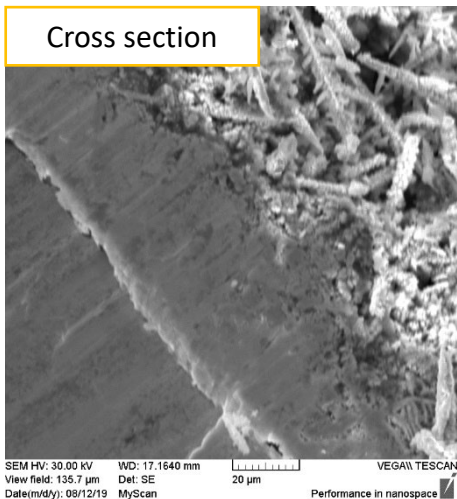
Characterization and Superconductivity Test

SEM & EDS

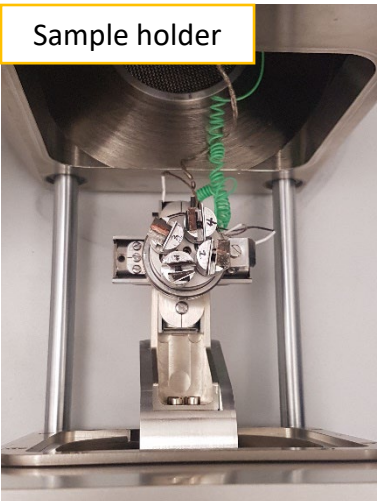
SEM apparatus



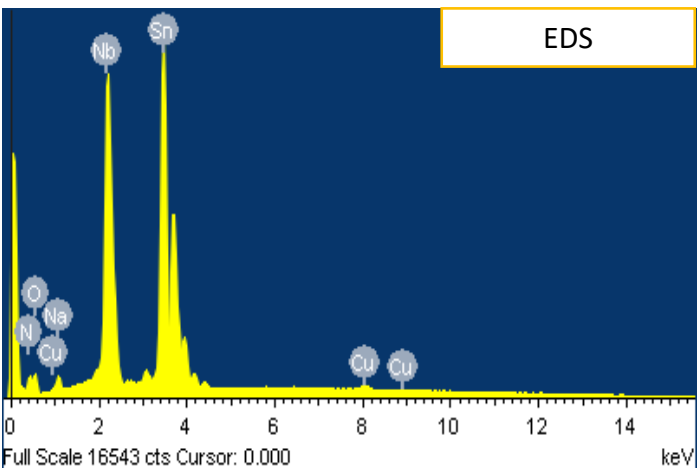
Cross section



Sample holder



EDS

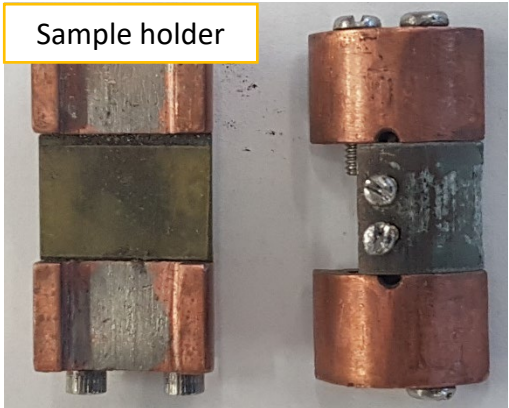


Superconductivity

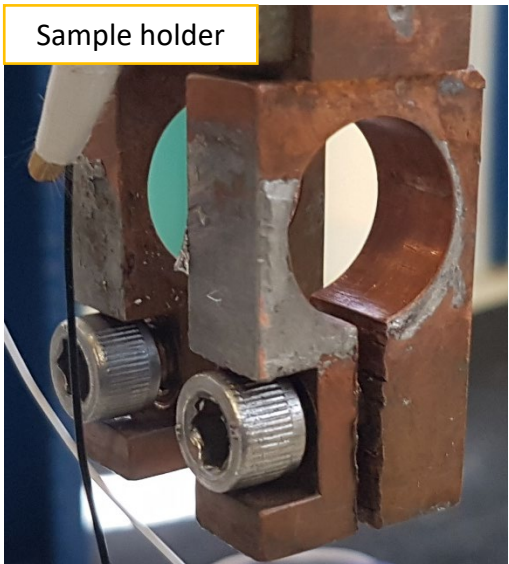
Cryostat



Sample holder



Sample holder



Goals

- 1 Definition of the current densities range that allows for the deposition of a continuous and homogeneous Nb₃Sn superconducting thin-film
- 2 Improvement of the surface homogeneity (border effect)
- 3 Substrate roughness/ peeling off relationship
- 4 Testing the method feasibility on curved surfaces (Cylinders)
- 5 Deposition on Nb/Cu substrates

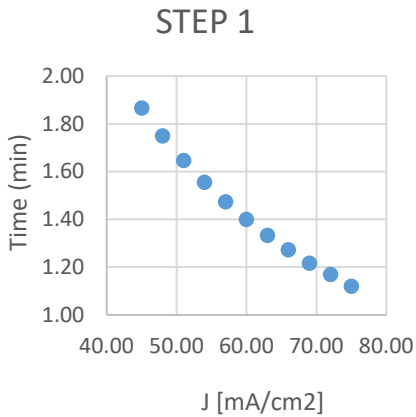
1: Definition of the current densities range














Starting from the electrochemical parameters of superconductive samples obtained last year, σ is kept constant, while J and t are varied across different samples

$$\sigma [C/cm^2] = J[A/cm^2] \cdot t[s]$$

σ : charge density
 J : current density

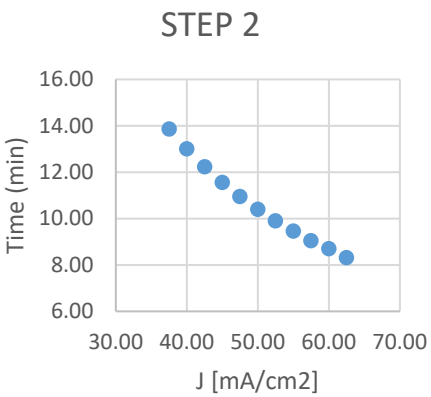
Deposition of Cu seed layer



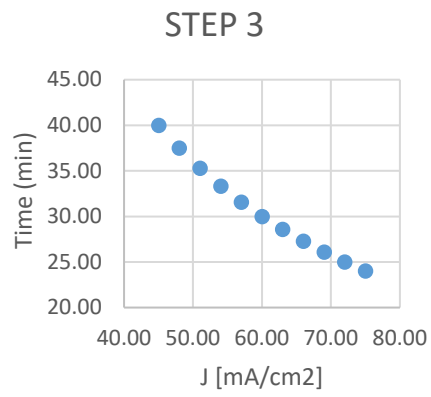
Higher current densities					Same exp. conditions used in previously deposited superconducting samples			Lower current densities				
+25 %	+20%	+15%	+10%	+5%	0	0	0	-5 %	-10%	-15%	-20%	-25%
												
					No tape	With tape	No grinding					

1: Definition of the current densities range

Deposition of Sn layer



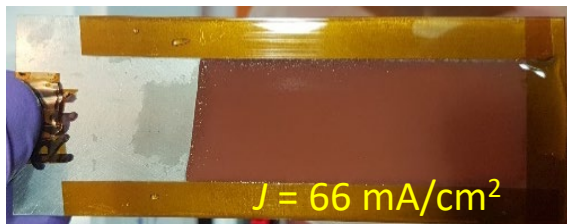
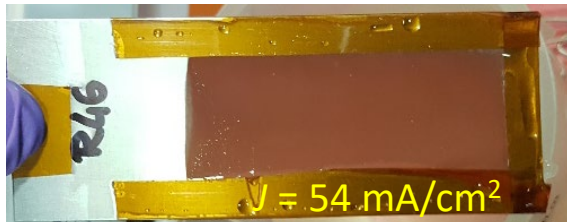
Deposition of Cu barrier layer



1: Definition of the current densities range

Cu seed layer

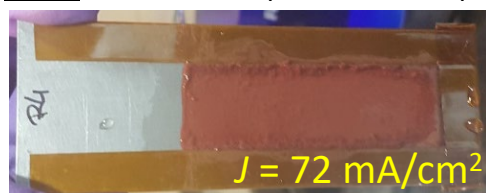
$$-10\% \leq J \leq +10\%$$
$$54 \text{ mA/cm}^2 \leq J \leq 66 \text{ mA/cm}^2$$



At low J: non homogeneous deposition

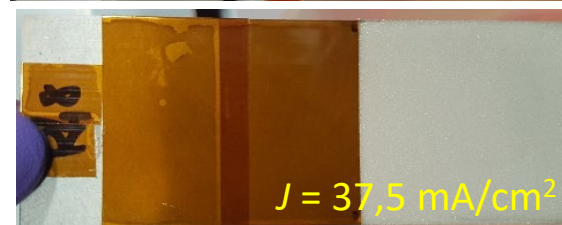
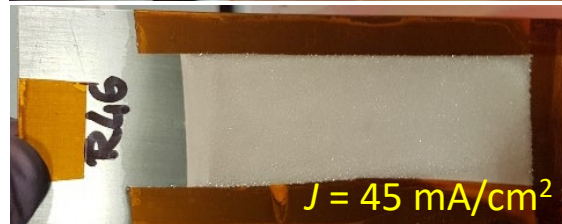
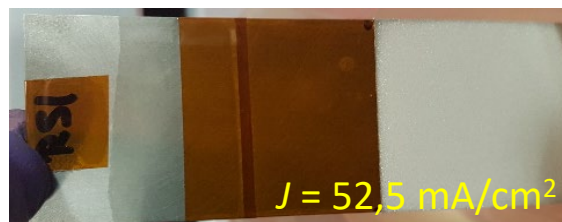


At high J: formation of powder like deposits

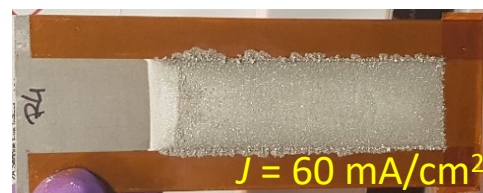


Sn layer

$$J \leq +5\%$$
$$J \leq 52,5 \text{ mA/cm}^2$$



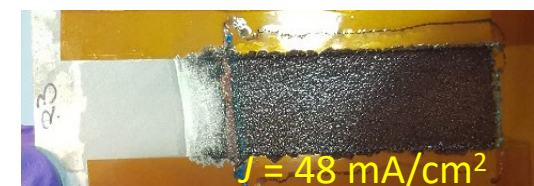
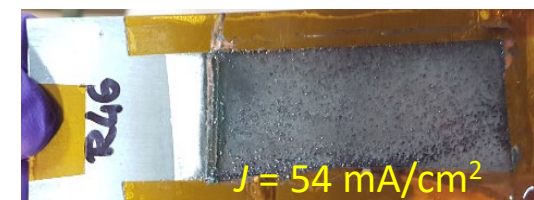
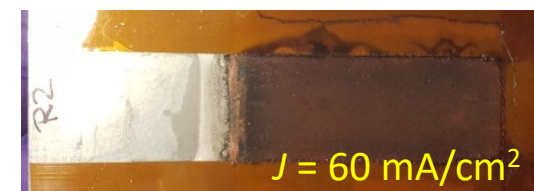
At high J: formation of powder like deposits



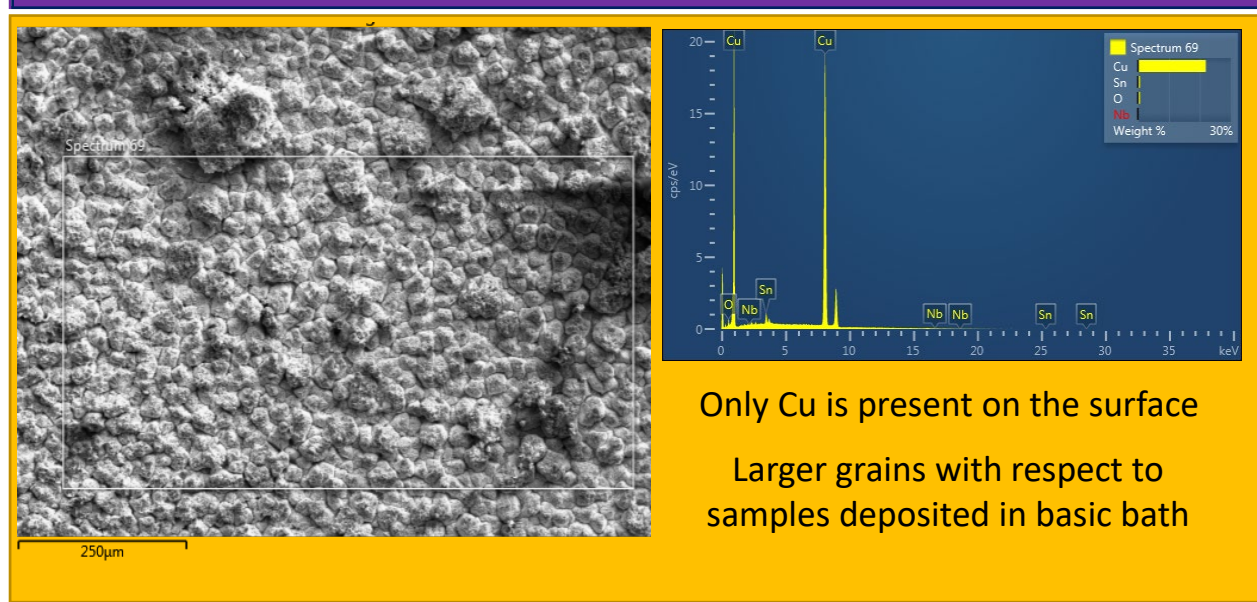
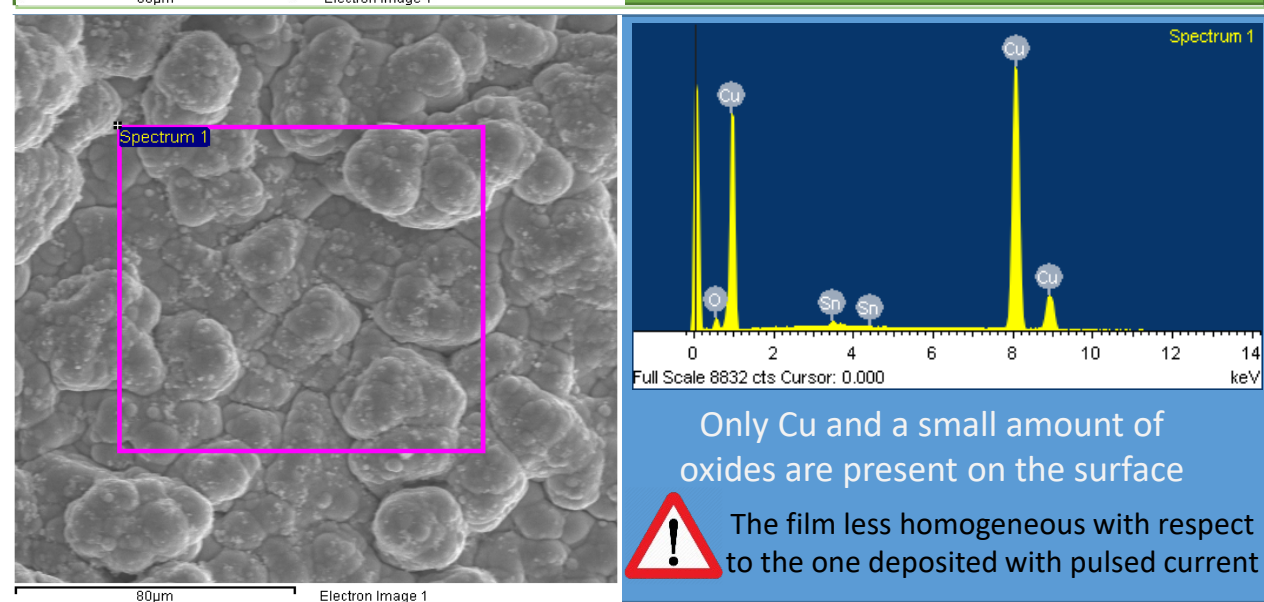
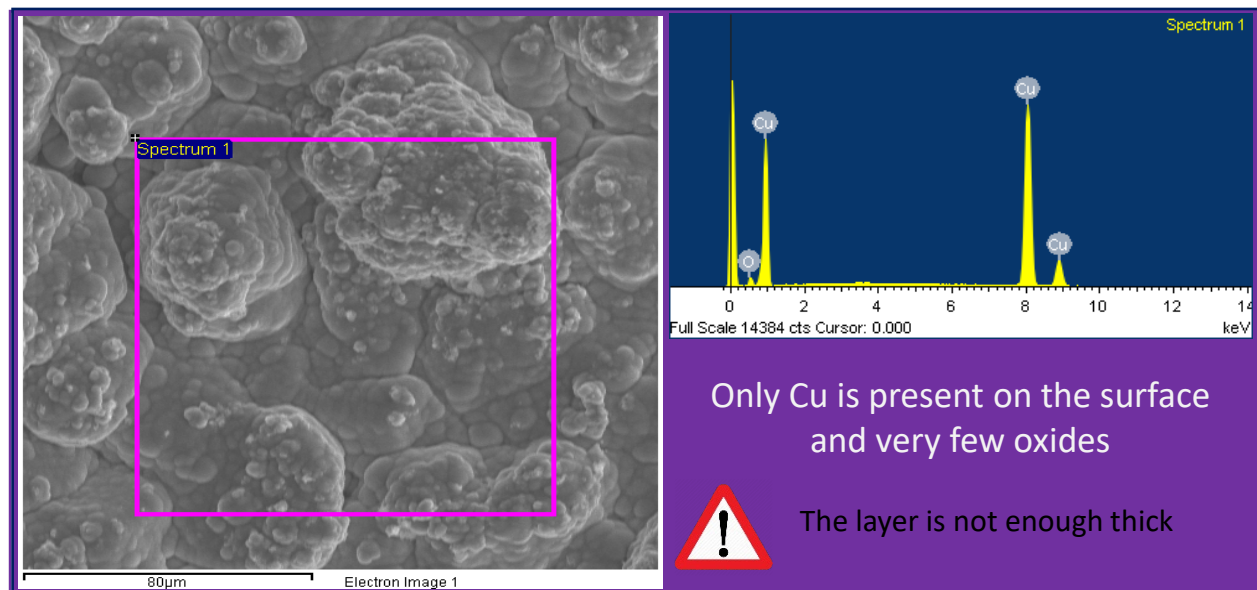
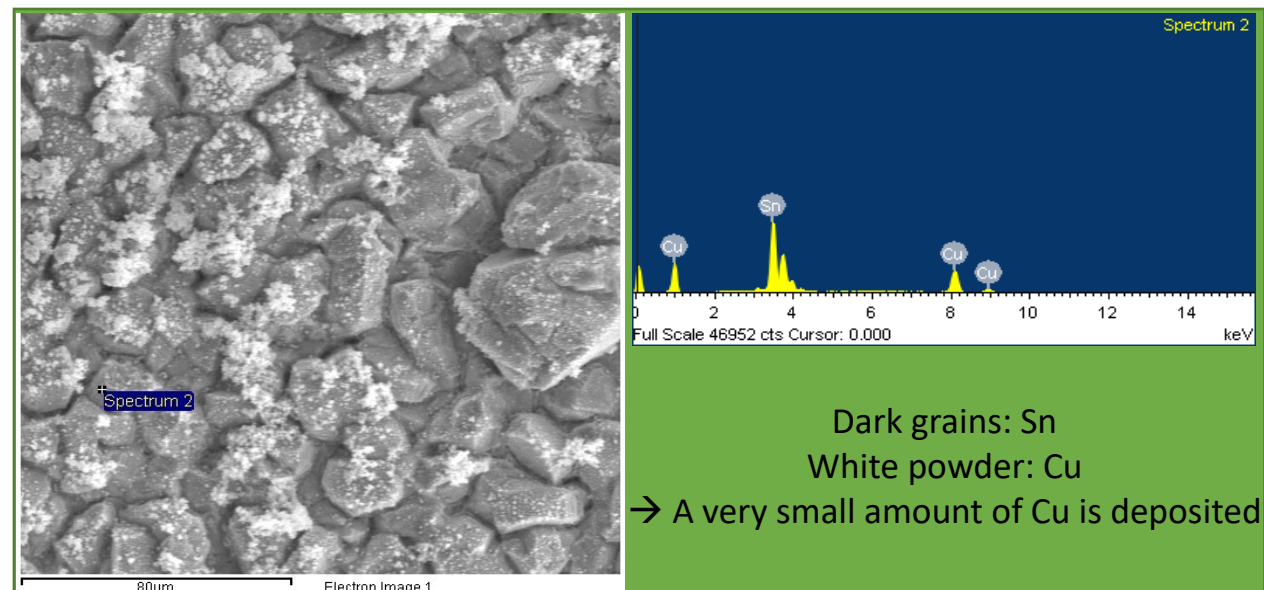
Cu barrier layer

All samples are covered by dark powder like deposits = oxides

- Dark Red deposits = Cu_2O
- Black deposits = CuO
- Green areas = bronze patina

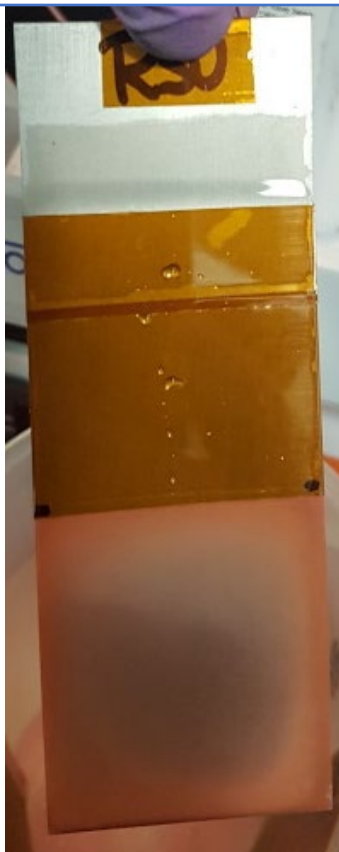


Deposition of the Cu barrier layer



2: Improvement of the surface homogeneity

Border effect: on the edges of the samples the electric field is higher than in the center → the current density on the edges is higher than in the center



No tape



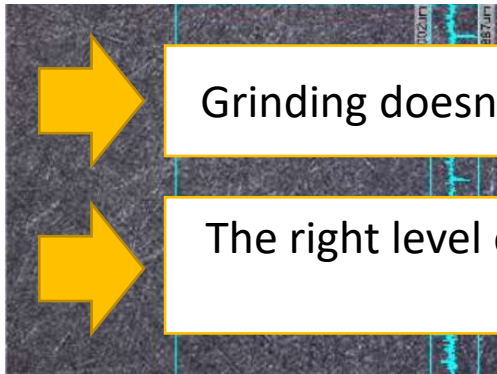
Tape

3: Substrate roughness/ peeling off relation

How roughness affects the adhesion of the deposited film?

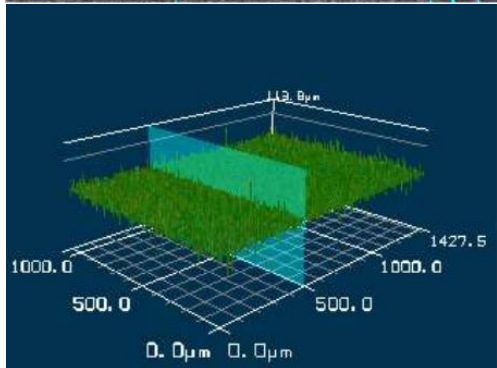
How to properly treat Nb before the deposition?

No grinding, only HF



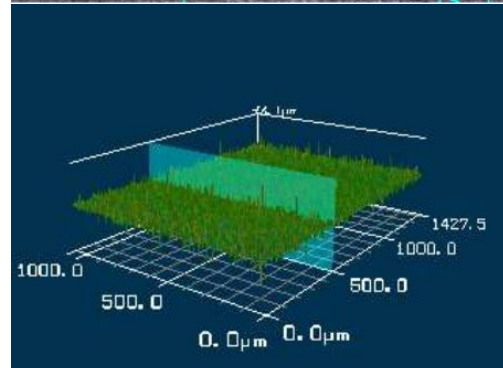
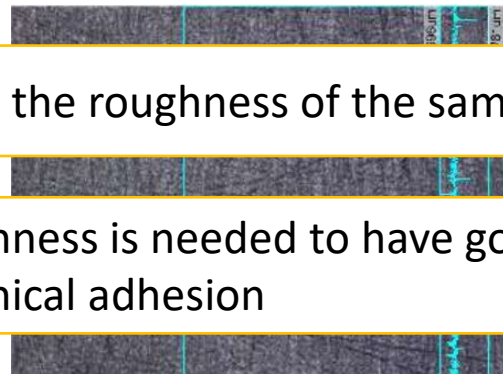
Grinding doesn't affect the roughness of the sample

The right level of roughness is needed to have good mechanical adhesion



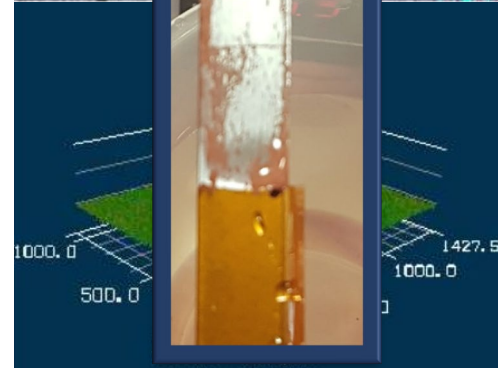
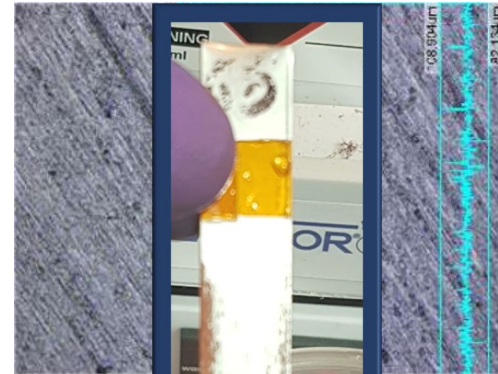
$R_a \approx 1,8 \mu\text{m}$

Grinding + HF



$R_a \approx 1,8 \mu\text{m}$

BCP + HF



$R_a \approx 1,5 \mu\text{m}$

Electro polishing + HF

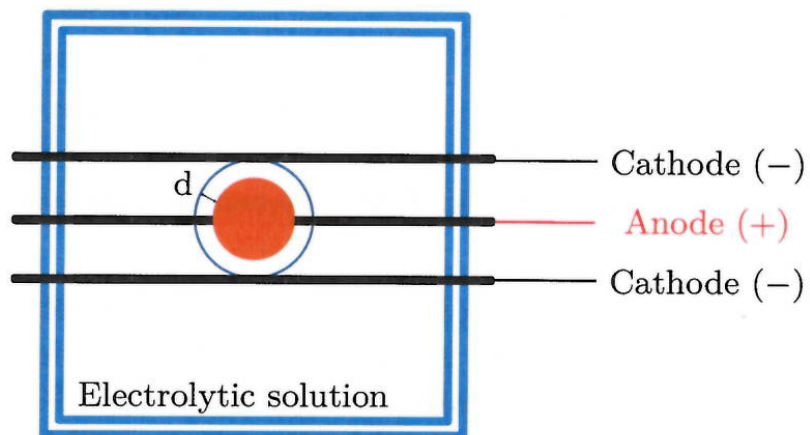


$R_a \approx 0,3 \mu\text{m}$

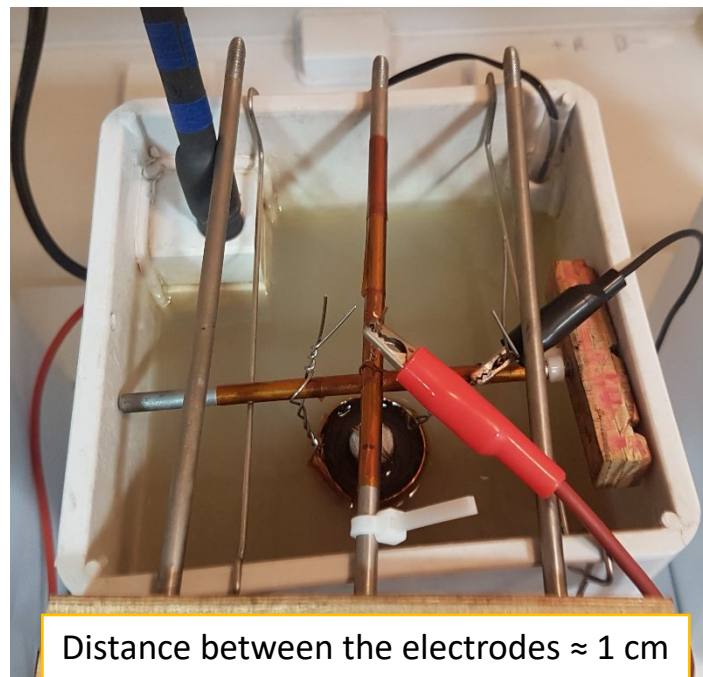
4: Testing the method feasibility on curved surfaces

Depositions on cylinders have been carried out once understood which are the best electrochemical conditions for plates

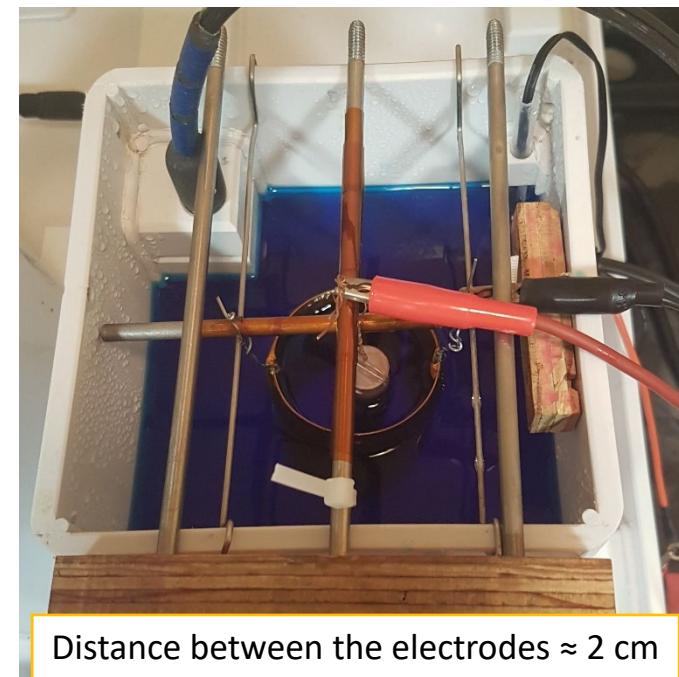
2 electrode geometry



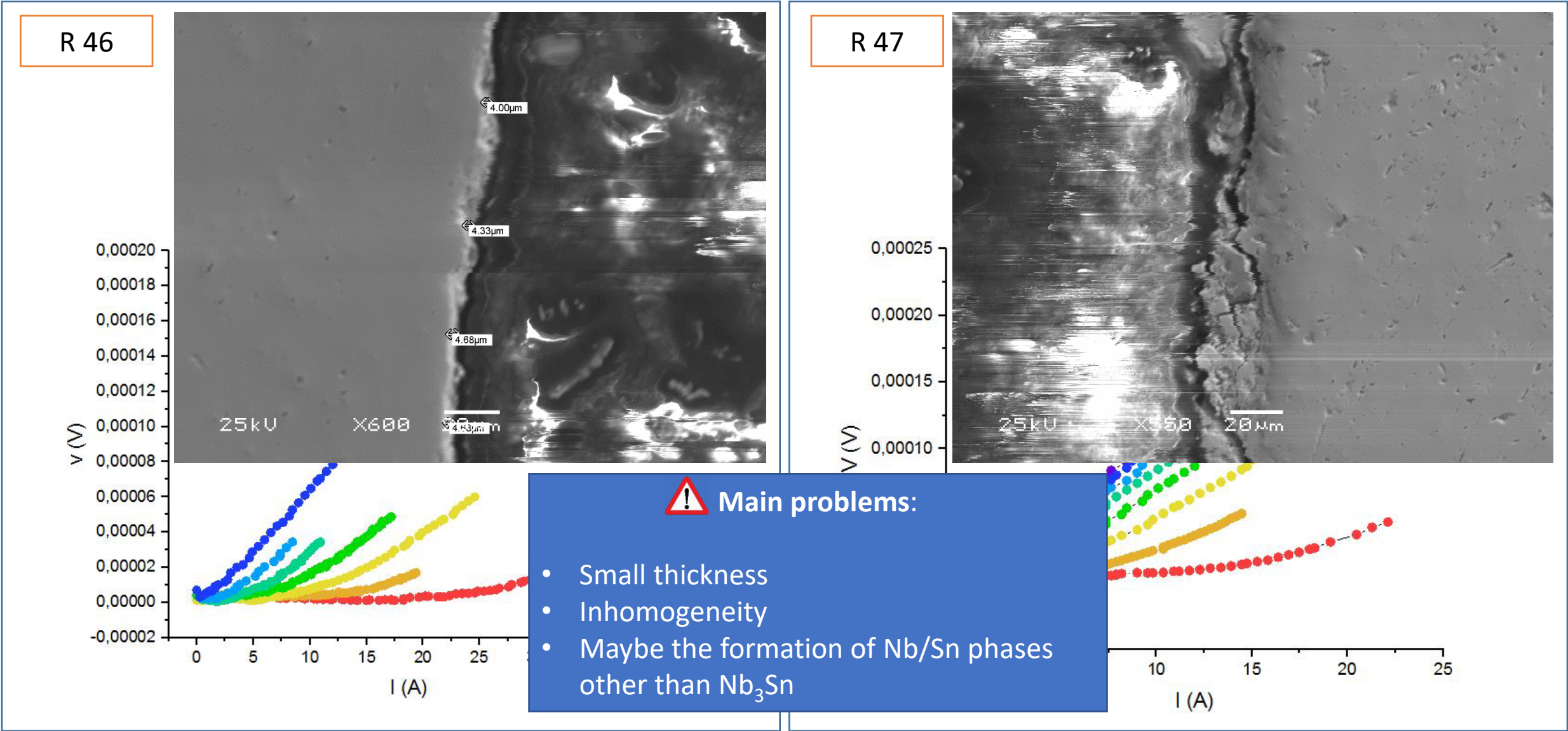
Small cylinders



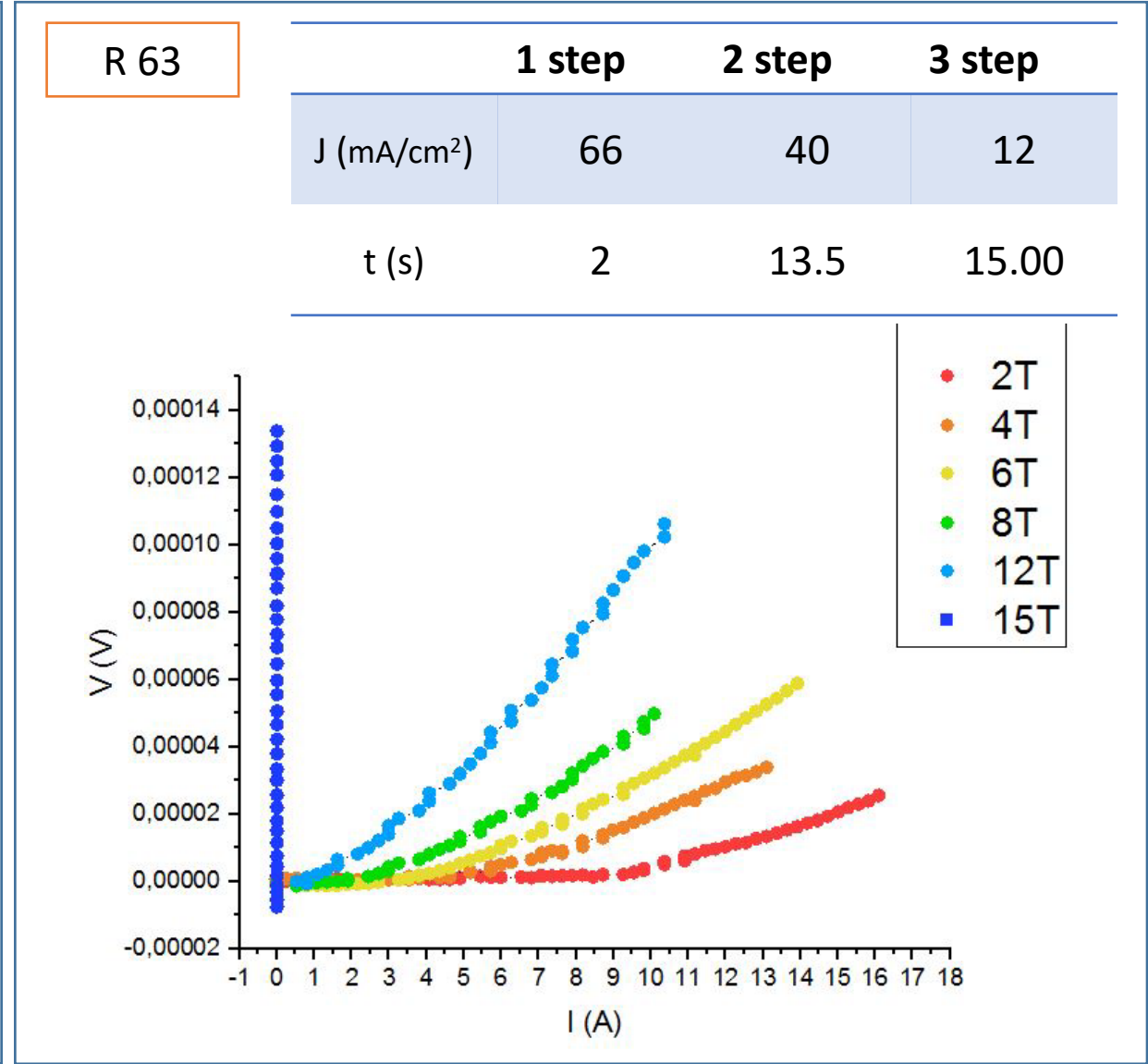
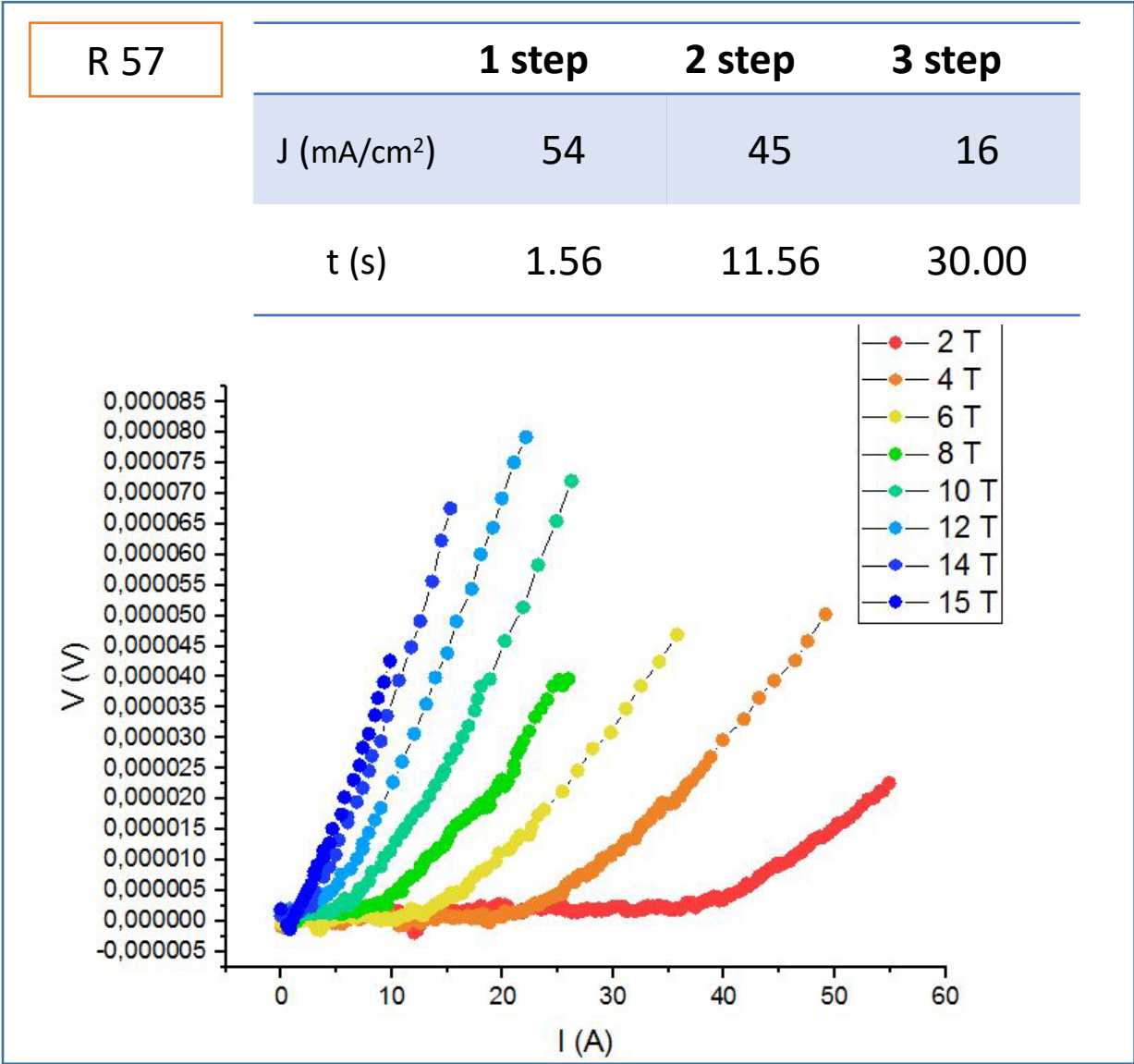
Large cylinders



Superconductivity tests

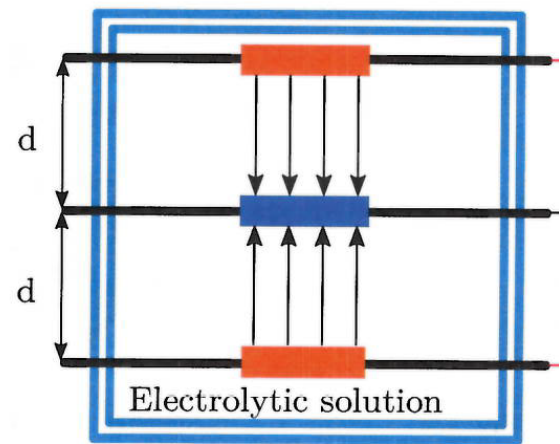


Superconductivity tests



What's next?

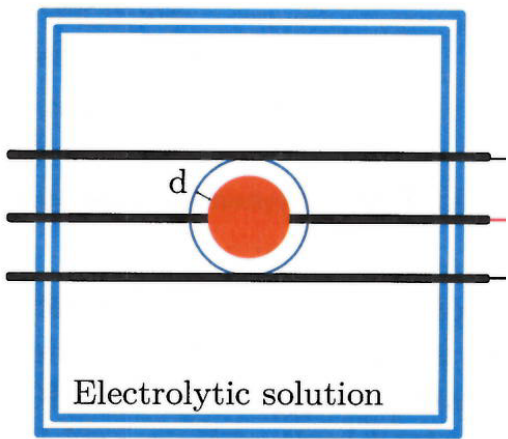
Deposition of new flat samples



Is this procedure highly reproducible?

Can geometry related problems be avoided?

Deposition on new cylinders



Can curved and flat shapes be plated with the same exp. conditions?

Are the results in terms of morphology and superconductivity the same?

Deposition on Nb/Cu disks



Cu barrier layer
Sn layer
Cu seed layer
Sputtered Nb layer
Cu substrate

Thermal treatment



If Sn < stoichiometric



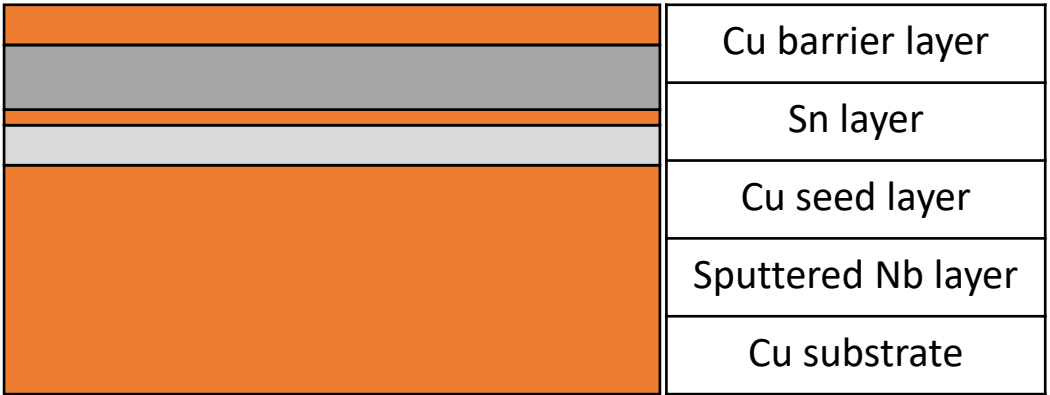
Bronze
Nb ₃ Sn
Nb
Cu

If Sn > stoichiometric



Bronze
Nb ₃ Sn
Bronze
Cu

5:Deposition on Nb/Cu substrates



Sputtered Nb on Cu



Extremely flat surface:
 $R_a \approx 0,5 \mu\text{m}$
↓
Grinding procedure is needed

